

Study of low- and hyperthermal energy Ne^+ scattering from metal surfaces using mass-resolved ion-scattering spectrometry

A.Tolstogouzov, S.Daolio, C.Pagura
IPELP CNR, Padova, Italy

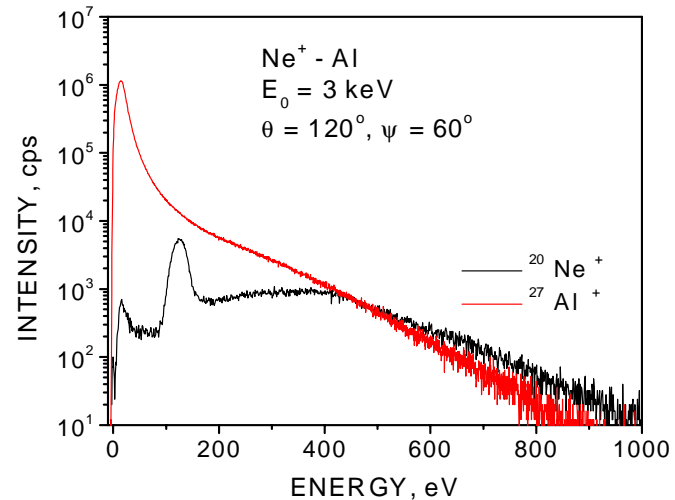
C.L. Greenwood
Hiden Analytical, Warrington, England

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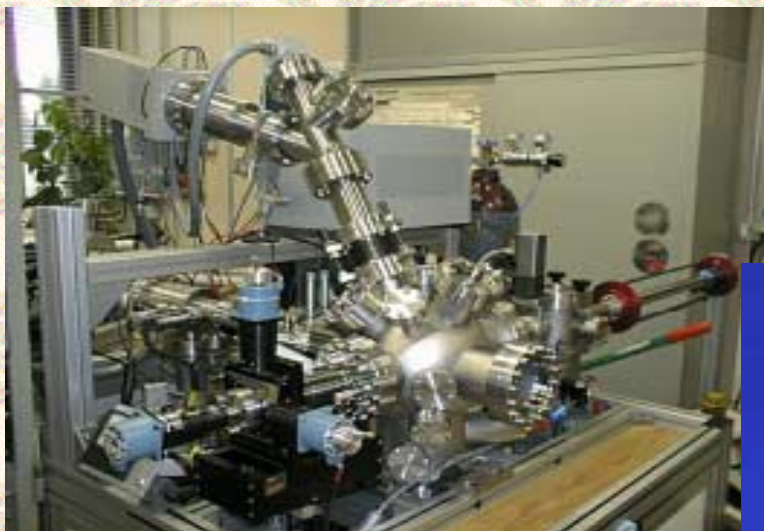
- **Mass-resolved Ion Scattering Spectrometry (MARISS):**
 - Basic principles
 - Experimental set-up
- **The study of neutralization of low-energy (0.5-1.5 keV) Ne⁺ scattered from the Cu-group metals and Pt:**
 - Updated dual-isotope method.
- **Hyperthermal (< 200 eV) Ne⁺scattering off Au and Pt:**
 - High energy peak (??)
- **Summary**

Compared with conventional low-energy ion scattering (LEIS), the MARISS technique:

- avoids interference between scattered and sputtered ions;
- suppresses the background related to doubly (or multiply) charged ions;
- provides a useful opportunity to operate with a “mixed” primary-ion beam containing different types of projectiles



Custom-built MARISS-SIMS instrument



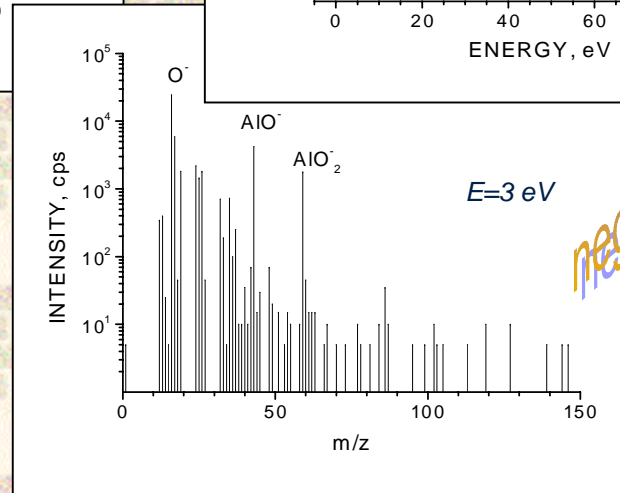
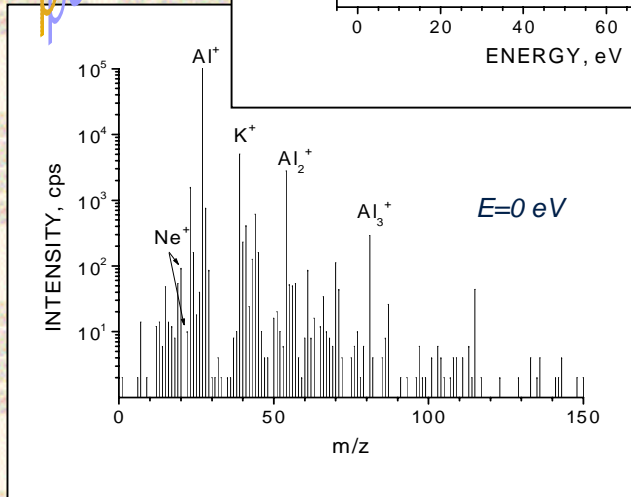
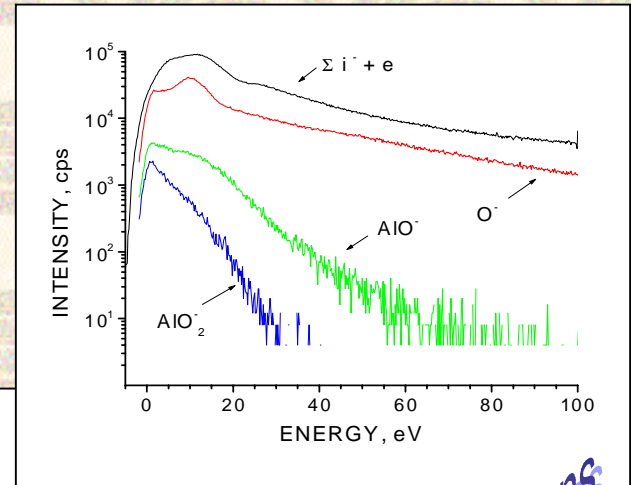
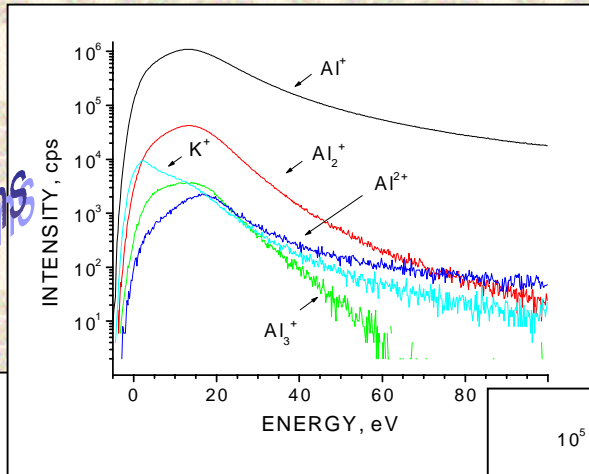
General view



Hiden EQS 1000 Mass Energy Analyser

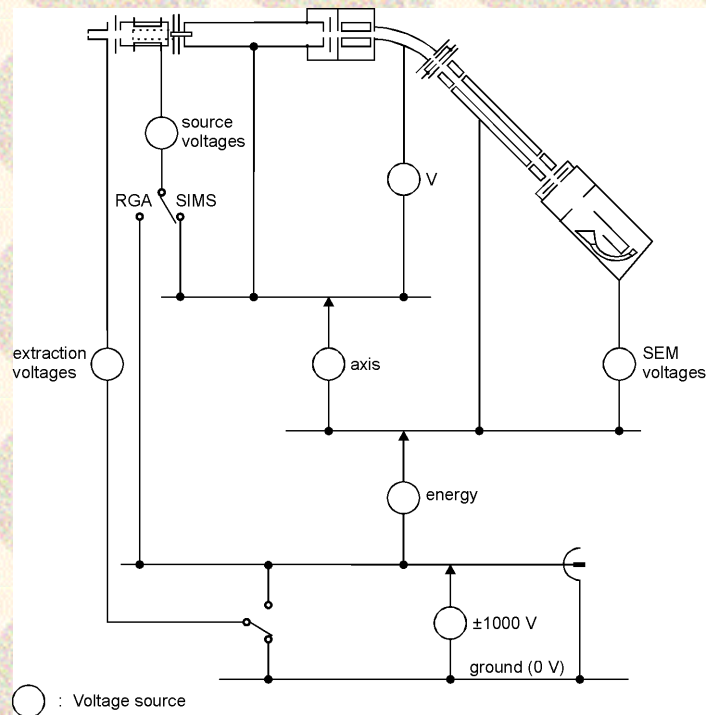
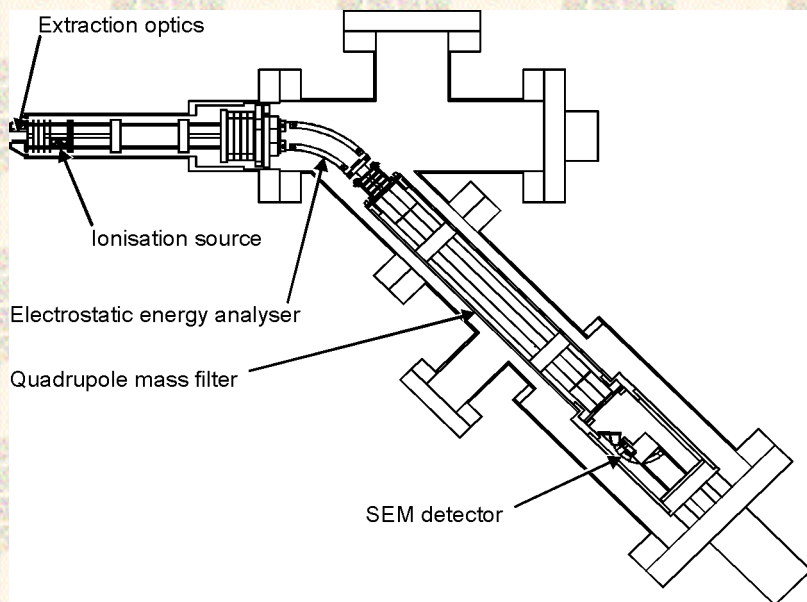
Our MARISS-SIMS set-up measures both energy resolved mass spectra and mass resolved energy distributions

positive ions



negative ions

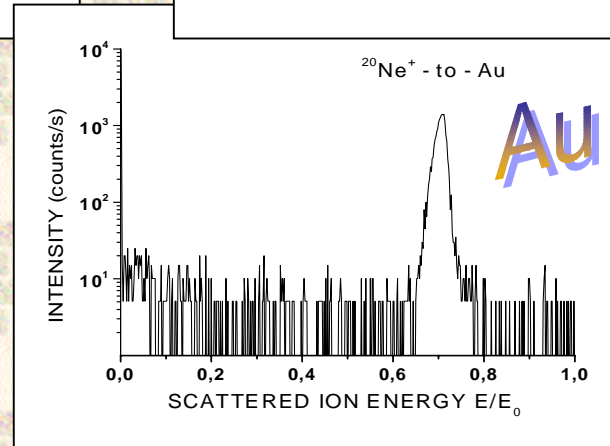
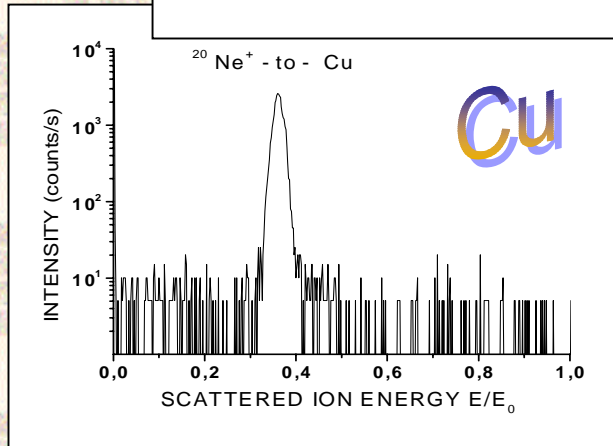
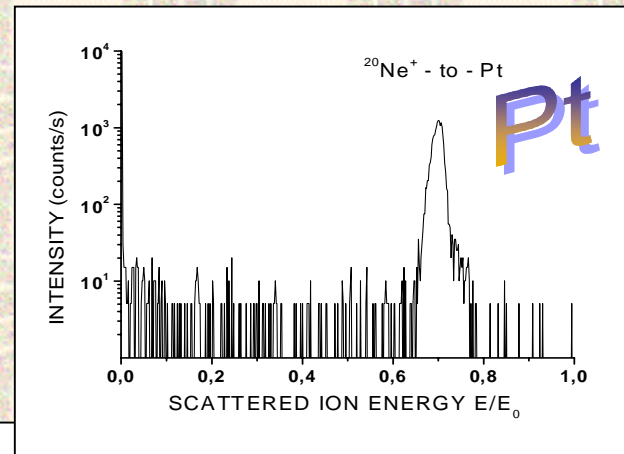
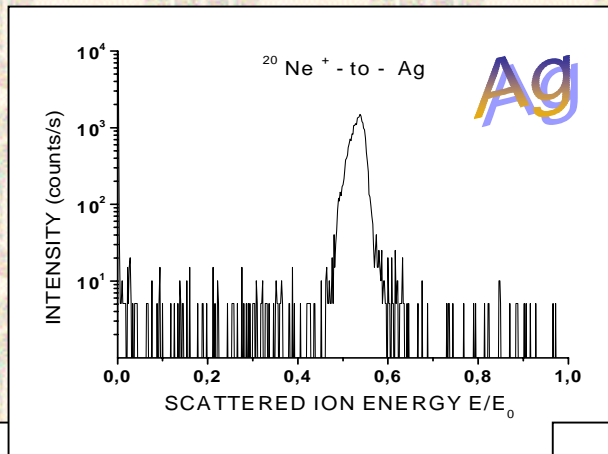
Hiden EQS 1000 Mass Energy Analyser



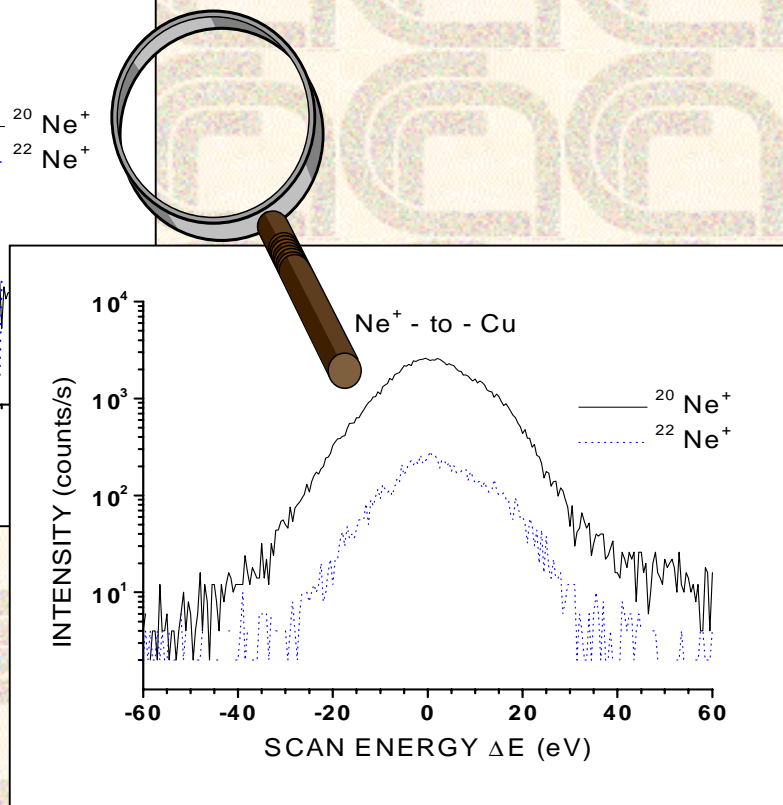
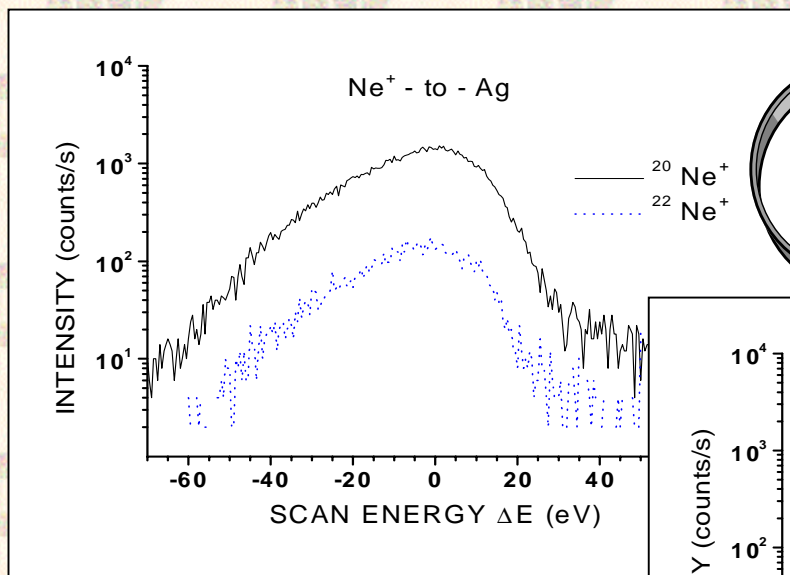
Experimental Conditions

- **EQS 1000 Mass Energy Analyser :**
 - energy resolution $\Delta E_a=3.5$ eV (FWHM) at $E_a=80$ eV;
 - energy scan of ± 1100 eV;
 - mass resolution $m/\Delta m=(5-10)m$ (FWHM) in the mass range 1-1000 m/z.
- **3M inert gas ion source:**
 - energy $E_0=0.05-5$ keV with $\Delta E_0=2-4$ eV ($I_{em}=10-15$ mA, $U_i=70-80$ V, $p=10^{-5}$ Torr, 99.99% pure Ne, without mass-separation);
 - current $I_0=10-1000$ nA with $d_0 < 3$ mm and angular divergence $\Delta\gamma=0.01-0.05$ rad.
- **“In-plane” specular reflection geometry:**
 - scattering angle $\theta=120^\circ$ with $\Delta\theta=1^\circ$ ($\Delta\Omega=10^{-4}$ sr);
 - incident angle $\psi=60^\circ$ (on the sample surface).
- **Samples studied were pure (99.9 %), polished, polycrystalline Cu, Ag, Au and Pt.**

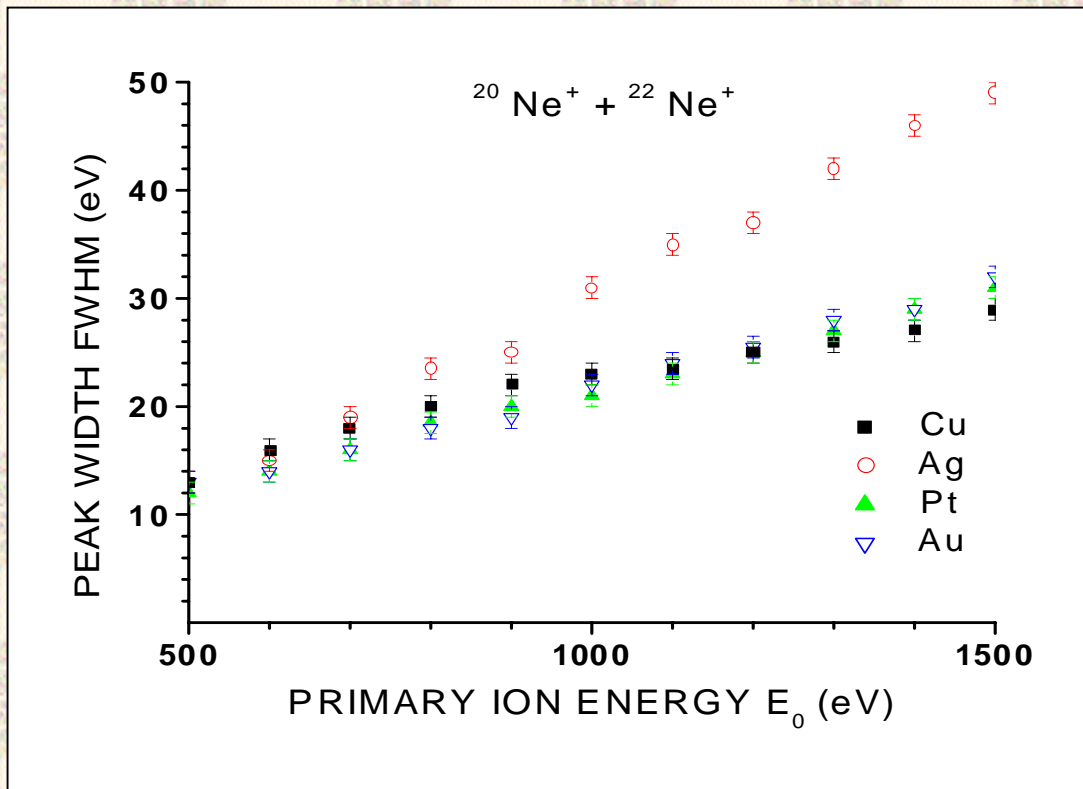
Mass-resolved energy spectra of $^{20}\text{Ne}^+$ scattered ions ($E_0 = 1 \text{ keV}$, $\theta = 120^\circ$, $\psi = 60^\circ$)



A close-up view of superposed scans for $^{20}\text{Ne}^+$ and $^{22}\text{Ne}^+$ scattered ions ...



... How the scattered peak FWHM depends on the primary-ion energy



The **ion scattering signal S** (*the binary elastic collision peak*), due to the i -component in the surface of the sample, can be written as:

$$S_i = I \cdot P_i^+ \cdot N_i \cdot \sigma_i \cdot F_i \cdot R \cdot \alpha_i$$

- I is the primary-ion current;
- P_i^+ is the **ion-survival probability**;
- N_i is the surface atom density;
- σ_i is the cross section per solid angle $\Delta\Omega$;
- F_i is an experimental factor including the analyser transmission and the detector efficiency;
- R is a correction factor for rough surfaces ($R=1$ for a flat surface);
- α_i is a steric factor taking into account shielding by neighboring atoms ($0 \leq \alpha_i \leq 1$).

If consider that only the Auger process is dominant, the **ion-survival probability P^+** is

$$P^+ = \exp(-v_c / v)$$

where $1/v = 1/v_{in} + 1/v_f$ with v_{in} and v_f being the normal components of velocities (Hagstrum) or total velocities (Godfrey-Woodruff) of the ion on the incoming and outgoing (final) parts of the trajectory respectively, and v_c is the **characteristic velocity** (neutralization constant) for the ion-target combination obtained by integrating the Auger transition rate over the length of the projectile trajectory.

The term $1/v$ represents the time that the particle spends near the surface, with **larger** values of v_c leading to a **smaller ion fraction** of the scattered particles.

Assuming that P^+ is a function of the reciprocal (inverse) velocities, it has become a custom to plot the natural logarithm of the normalized intensity **$\ln S$ versus $1/v$** by using the following **experimental approaches**:

- **variation of the scattering angle** at fixed primary energy or **variation of the primary energy** at a fixed scattering angle (*Brongersma et al.*);
- **angular distribution measurements** of ions scattered into the plane normal to that containing the incident beam and normal to the surface of the target with a fixed primary energy and a movable analyser (*O'Connor, MacDonald et al.*);
- **Dual-Isotope Surface Composition technique** (*Brongersma et al, Surf.Sci. 227 (1990) 361*) or **multi-isotope investigation** (*Wittmaack, Surf. Sci. 345 (1996) 110*)

Dual-Isotope Surface Composition (DISC) technique is based on the use of the two (or more) isotopes of the primary ions as projectiles

- *For a given incident energy E_0 , the lighter isotope ion has the higher velocity before and after collision;*
- *The neutralization constant v_c remains the same for all isotopes;*
- *The apparatus factors and sample characteristics are practically unaltered during dual-isotope scattering ion measurements.*

Our updated Dual-Isotope method involves the simultaneous use of $^{20}\text{Ne}^+$ and $^{22}\text{Ne}^+$ as projectiles with additional mass-separation of scattered ions

By using $^{20}\text{Ne}^+$ and $^{22}\text{Ne}^+$ as primary ions, one can find that

$$\ln\left(\frac{{}^{20}\text{S}}{{}^{22}\text{S}} \cdot \frac{{}^{22}\text{I}}{{}^{20}\text{I}} \cdot \frac{{}^{22}\sigma}{{}^{20}\sigma}\right) = v_c \cdot \left(\frac{1}{{}^{22}V} - \frac{1}{{}^{20}V}\right)$$

where the upper index of all factors indicates the mass of Ne^+ isotope ions. It is important to note that:

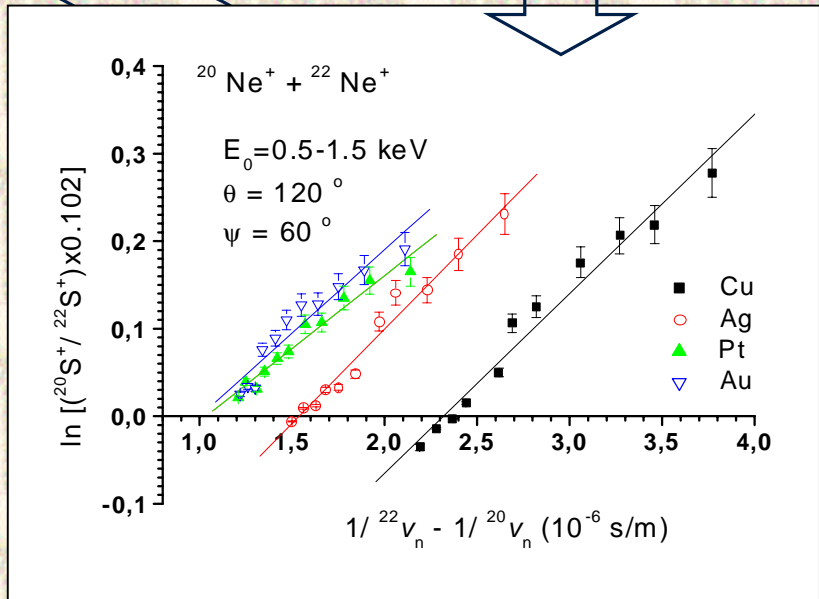
- **no precise primary-ion current measurements are needed**, because the relative primary current (${}^{22}\text{I}/{}^{20}\text{I}$) is equal to the natural neon isotopes ratio $k = 0.102$;
- the differential cross section is practically identical: for ZBL potential $({}^{22}\sigma/{}^{20}\sigma) = 1.005\text{-}1.01$ ($E_0 = 0.5\text{-}1.5$ keV and $\theta = 120^\circ$).

$$\ln\left(\frac{{}^{20}\text{S}}{{}^{22}\text{S}} \cdot 0.102\right) = v_c \cdot \left(\frac{1}{{}^{22}V} - \frac{1}{{}^{20}V}\right)$$

Plots of the natural logarithm of the peak intensity ratio versus the difference in reciprocal velocities

$$\ln\left(\frac{{}^{20}\text{S}}{{}^{22}\text{S}} \cdot 0.102\right) \approx A + v_c \cdot \left(\frac{1}{{}^{22}v} - \frac{1}{{}^{20}v}\right)$$

	$v_c \times 10^5 \text{ m/s}$	A
Cu	2.05 ± 0.12	-0.475 ± 0.033
Ag	2.15 ± 0.12	-0.332 ± 0.023
Pt	1.67 ± 0.10	-0.173 ± 0.019
Au	1.90 ± 0.20	-0.191 ± 0.031



Results of linear regression fitting of the experimental data (for comparison, $v_c = 1.36 \times 10^5 \text{ m/s}$ for Ne^+ -to-Au by Buck et al.)

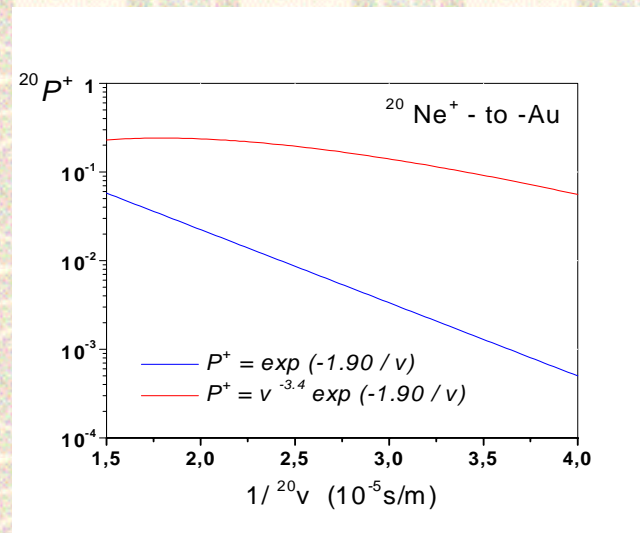
$$P^+ = (b/v^n) \cdot \exp(-v_c/v)$$

where **b** is the normalization factor and the index of the power

$$n = A/\ln\left(\frac{{}^{22}v}{{}^{20}v}\right)$$

Projectile parameters estimated for the “critical points”

Sample	E_0, keV	$r_0, \text{\AA}$	${}^{22}v, \times 10^4 \text{ m/s}$	${}^{20}v, \times 10^4 \text{ m/s}$	n
Cu	1.3	0.37	3.344	3.632	5.7
Ag	1.5	0.41	4.129	4.401	5.2
Pt*	2.1	0.43	5.323	5.627	3.1
Au*	2.1	0.43	5.322	5.629	3.4

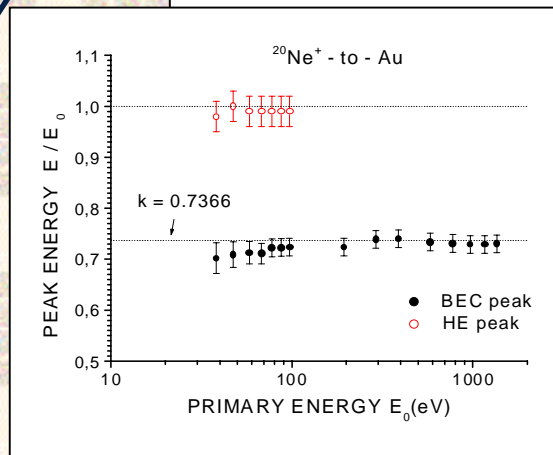
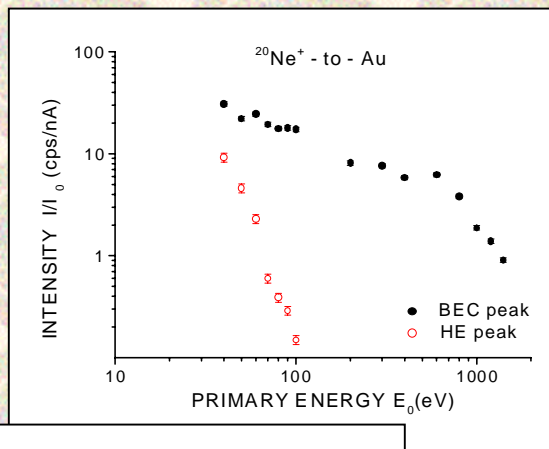
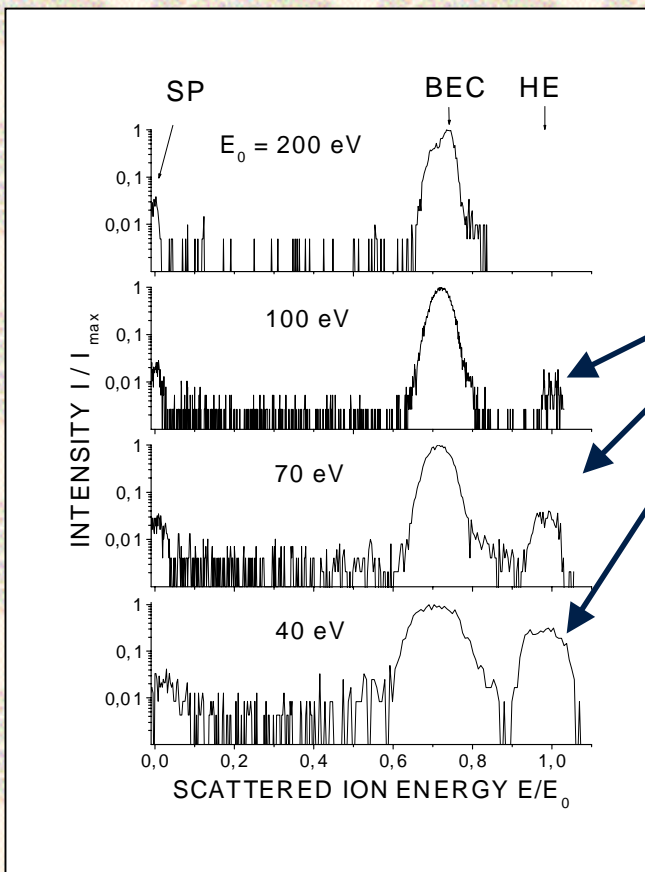


Ion-survival probability P^+ vs the reciprocal velocity

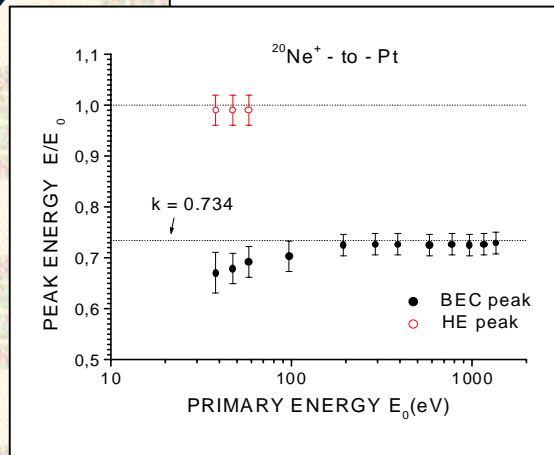
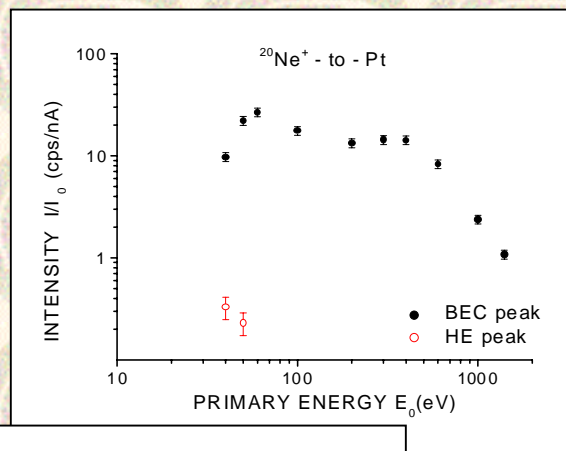
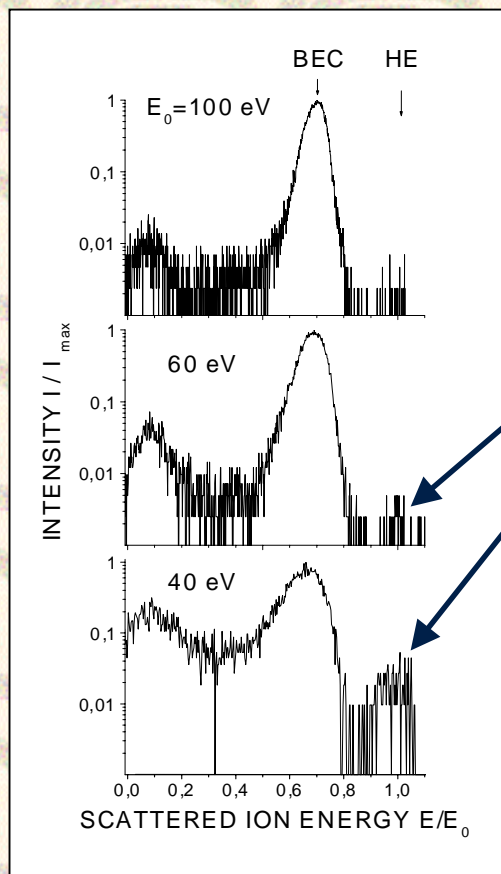
Conclusions

- *An updated dual-isotope method based on MARISS technique with two isotopes of Ne^+ as primary-ion beam was developed.*
- *The data for characteristic velocity v_c for Cu, Ag, Au and Pt were estimated.*
- *An empirical formula for $P^+(1/v)$, containing an additional term dependent on the reciprocal velocity, was suggested without monotone dependence of the ion-survival probability on the reciprocal velocity.*
- *The proposed expression is open to question and call for an adequate physical model based on ab-initio quantum calculation.*

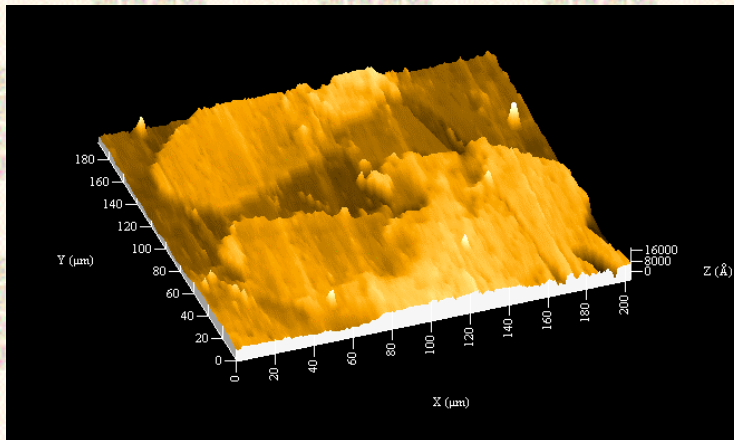
Hyperthermal energy Ne⁺ scattering from Au



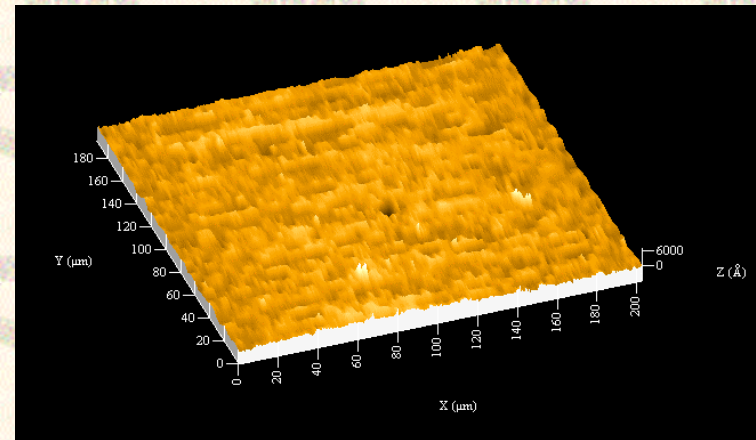
Hyperthermal energy Ne⁺ scattering from Pt



Surface topography measured after experiments by Tencor Profiler P-10 (a total ion dose was about 10^{16} cm^{-2})

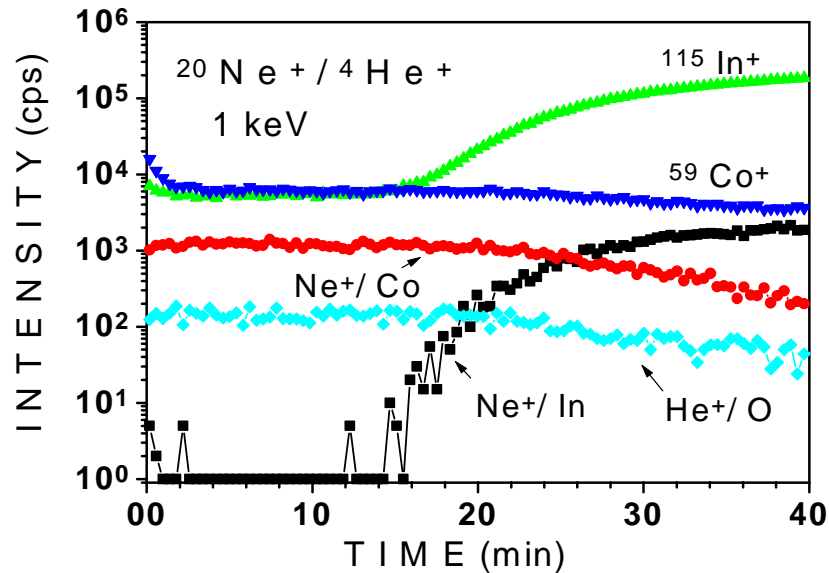


Au sample (*rms roughness is about $210 \pm 130 \text{ nm}$*)



Pt sample (*rms roughness is about $92 \pm 8.5 \text{ nm}$*)

SIMS-MARISS depth profiles of cobalt oxide film (about 25 nm) on indium tin oxide (ITO) substrate



Primary ions - $\text{Ne}^+ + \text{He}^+$, 1 keV / $1 \mu\text{A}$, $2 \times 2 \text{ mm}^2$, 20% el. gating, $\theta = 120^\circ$.
 Peaks of interest: SIMS - $^{115}\text{In}^+$, $^{59}\text{Co}^+$; MARISS - $^{20}\text{Ne}^+$ -to-In (596 eV),
 $^{20}\text{Ne}^+$ -to-Co (352 eV), $^4\text{He}^+$ -to-O (474 eV)

“Significant items in a given group normally constitute a relatively small part of the total items”

Vilfredo Pareto,
an Italian sociologist and economist